

#50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C Aging at 25°C #50pm/Maximum Operating Temperature Range -20°C to +70°C Supply Voltage 5.0Vdc ±10% Aptimum 45mA Maximum (Unloaded) Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Nise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Load Drive Capability 50pF HCMOS Load Maximum Dutput Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum Start Up Time 10mSec Maximum Romage Temperature Range -55°C to +125°C EINVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	ELECTRICAL SPECIFICATIONS		
Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration) Aging at 25°C ±5ppm/year Maximum Operating Temperature Range -20°C to +70°C Supply Voltage 5.0Vdc ±10% nput Current 45mA Maximum (Unloaded) Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 20% to 80% of waveform) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 20% to 80% of waveform) Dutput Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Load Drive Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) ±2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 30mA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 8pSec Typical Stard Peak Jitter (tPK) 100pSec Maximum, 8pSec Typical NIN Period Jitter (tPKS)	Nominal Frequency	40.160MHz	
Operating Temperature Range -20°C to +70°C Supply Voltage 5.0Vdc ±10% nput Current 45mA Maximum (Unloaded) Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Dutp Voltage Logic Low (Vol) 0.4Vdc Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) .coad Drive Capability 50pF HCMOS Load Maximum Dutput Voltage (Vih and Vil) ±2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tPK) 100pSec Maximum, 8pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum Storage Temperature Range =55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Frequency Tolerance/Stability	Operating Temperature Range, Supply Voltage Change, Output Load Change,	
Supply Voltage 5.0Vdc ±10% nput Current 45mA Maximum (Unloaded) Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Dutp Voltage Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 8pSec Typical RMS Period Jitter (tPK) 100pSec Maximum, 8pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Aging at 25°C	±5ppm/year Maximum	
AtsmA Maximum (Unloaded) Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Soad Drive Capability SopF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current S0µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Stard Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Operating Temperature Range	-20°C to +70°C	
Dutput Voltage Logic High (Voh) Vdd-0.4Vdc Minimum (IOH = -16mA) Output Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Output Voltage Logic Low (Vol) 50 ±10(%) (Measured at 20% to 80% of waveform) Output Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) SopF HCMOS Load Maximum 50pF HCMOS Load Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) +1 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tPK) 100pSec Maximum, 8pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Supply Voltage	5.0Vdc ±10%	
Dutput Voltage Logic Low (Vol) 0.4Vdc Maximum (IOL = +16mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Load Drive Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tPK) 10pSec Maximum, 8pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Input Current	45mA Maximum (Unloaded)	
Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Load Drive Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tPK) 100pSec Maximum, 8pSec Typical Stard Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Output Voltage Logic High (Voh)	Vdd-0.4Vdc Minimum (IOH = -16mA)	
Duty Cycle 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) Load Drive Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum, 50pSec Typical RMS Period Jitter (tPK) 100pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMEENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Output Voltage Logic Low (Vol)	0.4Vdc Maximum (IOL = +16mA)	
Join Drive Capability 50pF HCMOS Load Maximum Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Rise/Fall Time	4nSec Maximum (Measured at 20% to 80% of waveform)	
Dutput Logic Type CMOS Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Duty Cycle	50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load)	
Pin 1 Connection Tri-State (Disabled Output: High Impedance) Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum (Pin 1 = Ground) Deak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Load Drive Capability	50pF HCMOS Load Maximum	
Pin 1 Input Voltage (Vih and Vil) +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. Standby Current 50µA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Output Logic Type	CMOS	
Standby Current 50μA Maximum (Pin 1 = Ground) Disable Current 30mA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Pin 1 Connection	Tri-State (Disabled Output: High Impedance)	
Disable Current 30mA Maximum (Pin 1 = Ground) Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Pin 1 Input Voltage (Vih and Vil)	+2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output.	
Peak to Peak Jitter (tPK) 100pSec Maximum, 50pSec Typical RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Standby Current	50µA Maximum (Pin 1 = Ground)	
RMS Period Jitter (tRMS) 13pSec Maximum, 8pSec Typical Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Disable Current	30mA Maximum (Pin 1 = Ground)	
Start Up Time 10mSec Maximum Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Peak to Peak Jitter (tPK)	100pSec Maximum, 50pSec Typical	
Storage Temperature Range -55°C to +125°C ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	RMS Period Jitter (tRMS)	13pSec Maximum, 8pSec Typical	
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS Fine Leak Test MIL-STD-883, Method 1014, Condition A	Start Up Time	10mSec Maximum	
Fine Leak Test MIL-STD-883, Method 1014, Condition A	Storage Temperature Range	-55°C to +125°C	
	ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Gross Leak Test MIL-STD-883 Method 1014 Condition C	Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
	Gross Leak Test	MIL-STD-883, Method 1014, Condition C	

MIL-STD-883, Method 2004

MIL-STD-202, Method 210

MIL-STD-202, Method 215

MIL-STD-883, Method 2003

MIL-STD-883, Method 1010

MIL-STD-202, Method 213, Condition C

MIL-STD-883, Method 2007, Condition A

Lead Integrity

Solderability

Vibration

Mechanical Shock

Resistance to Solvents

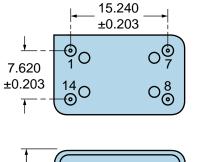
Temperature Cycling

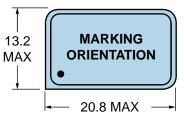
Resistance to Soldering Heat

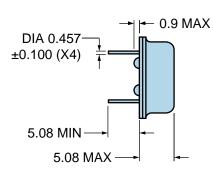
EP1145TSC-40.160M



MECHANICAL DIMENSIONS (all dimensions in millimeters)

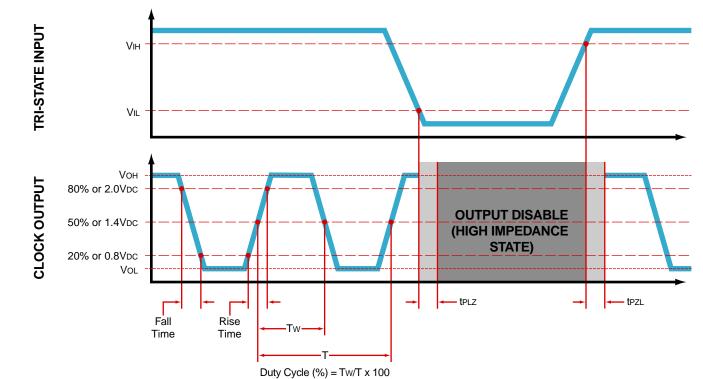






PIN	CONNECTION
1	Tri-State (High Impedance)
7	Ground/Case Ground
8	Output
14	Supply Voltage
LINE	MARKING
1	ECLIPTEK
2	EP11TS EP11=Product Series
3	40.160M
4	XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

OUTPUT WAVEFORM & TIMING DIAGRAM

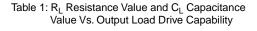


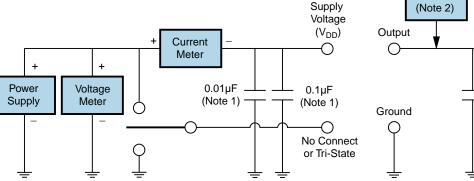
EP1145TSC-40.160M



Test Circuit for TTL Output

Output Load Drive Capability	R _L Value (Ohms)	C _L Value (pF)
10TTL	390	15
5TTL	780	15
2TTL	1100	6
10LSTTL	2000	15
1TTL	2200	3





Probe (Note 2) Output Ground Ground CL (Note 3)

Frequency

Counter

Oscilloscope

Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

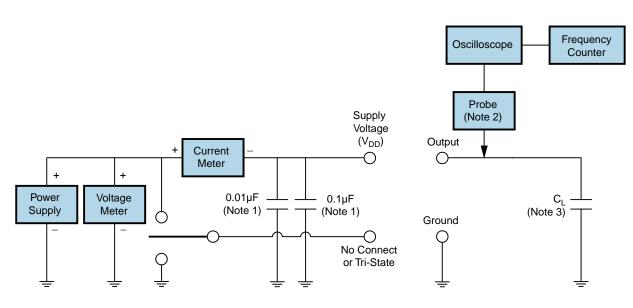
Note 4: Resistance value RL is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.

Note 5: All diodes are MMBD7000, MMBD914, or equivalent.

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Test Circuit for CMOS Output



Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_1 includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods

EP1145TSC-40.160M



High Temperature Solder Bath (Wave Solder)

T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
- Temperature Maximum (T _s MAX)	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T _L to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _P)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.



Recommended Solder Reflow Methods

EP1145TSC-40.160M



Low Temperature Infrared/Convection 185°C

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
 Temperature Typical (T_s TYP) 	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T _L to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	185°C Maximum
Target Peak Temperature (T _P Target)	185°C Maximum 2 Times
Time within 5°C of actual peak (t _P)	10 seconds Maximum 2 Times
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option.



Recommended Solder Reflow Methods

EP1145TSC-40.160M



Low Temperature Solder Bath (Wave Solder)

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	N/A
- Temperature Typical (T _s TYP)	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	30 - 60 Seconds
Ramp-up Rate (T _L to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	245°C Maximum
Target Peak Temperature (T _P Target)	245°C Maximum 1 Time / 235°C Maximum 2 Times
Time within 5°C of actual peak (t _p)	5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)